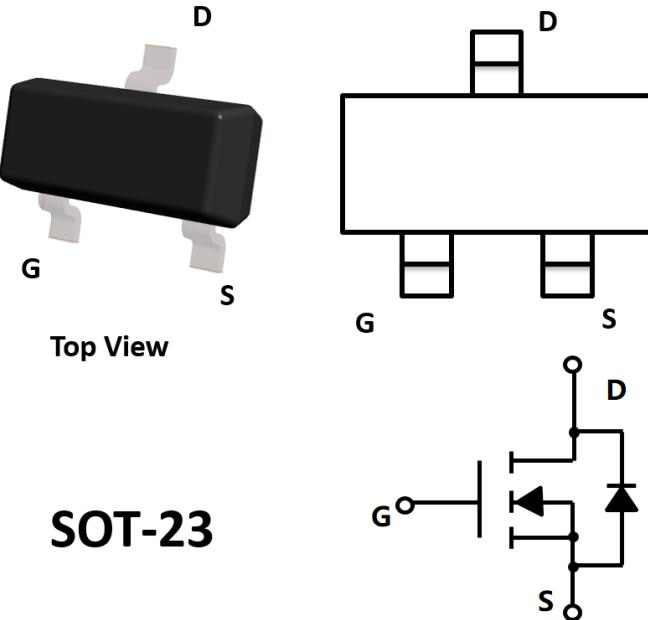


N-Channel Enhancement Mode Field Effect Transistor

RC03N06B

Product Summary

- V_{DS} 60V
- I_D 3.0A
- $R_{DS(ON)}$ (at $V_{GS} = 10V$) <100mohm
- $R_{DS(ON)}$ (at $V_{GS} = 4.5V$) <120mohm
- $R_{DS(ON)}$ (at $V_{GS} = 2.5V$) <200mohm



General Description

- Trench Power LV MOSFET technology
- High Density Cell Design for Low $R_{DS(ON)}$
- High Speed switching

Applications

- Battery protection
- Load switch
- Power management

■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-source Voltage	V_{DS}	60	V
Gate-source Voltage	V_{GS}	± 16	V
Drain Current $T_A=25^\circ\text{C}$	I_D	3	A
$T_A=70^\circ\text{C}$		2.4	
Pulsed Drain Current ^A	I_{DM}	12	A
Total Power Dissipation @ $T_A=25^\circ\text{C}$ Steady State	P_D	1.2	W
Thermal Resistance Junction-to-Ambient ^B	$R_{\theta JA}$	105	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range	T_J, T_{STG}	-55~+150	$^\circ\text{C}$

■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
RC03N06B	F2		3000	30000	180000	7" reel

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■ Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}= 60\text{V}, V_{\text{GS}}=0\text{V}$			1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 16\text{V}, V_{\text{DS}}=0\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}= V_{\text{GS}}, I_{\text{D}}= 250\mu\text{A}$	0.65	0.95	1.55	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}= 10\text{V}, I_{\text{D}}= 3\text{A}$		65	100	$\text{m}\Omega$
		$V_{\text{GS}}= 4.5\text{V}, I_{\text{D}}= 2\text{A}$		75	120	
		$V_{\text{GS}}= 2.5\text{V}, I_{\text{D}}= 1\text{A}$		100	200	
Diode Forward Voltage	V_{SD}	$I_{\text{S}}= 3.0\text{A}, V_{\text{GS}}=0\text{V}$		0.8	1.2	V
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHZ}$		451		pF
Output Capacitance	C_{oss}			38		
Reverse Transfer Capacitance	C_{rss}			31		
Switching Parameters						
Total Gate Charge	Q_g	$V_{\text{GS}}= 10\text{V}, V_{\text{DS}}= 30\text{V}, I_{\text{D}}= 3.0\text{A}$		13.8		nC
Gate-Source Charge	Q_{gs}			2.2		
Gate-Drain Charge	Q_{gd}			1.9		
Reverse Recovery Charge	Q_{rr}	$I_F= 3\text{A}, dI/dt=100\text{A/us}$		7.6		ns
Reverse Recovery Time	t_{rr}			30		
Turn-on Delay Time	$t_{\text{D(on)}}$			3		
Turn-on Rise Time	t_r	$V_{\text{GS}}= 10\text{V}, V_{\text{DS}}= 30\text{V}, I_{\text{D}}= 1.5\text{A}$ $R_{\text{GEN}}= 3\Omega$		18		ns
Turn-off Delay Time	$t_{\text{D(off)}}$			17		
Turn-off fall Time	t_f			22		

A. Pulse Test: Pulse Width $\leq 300\text{us}$, Duty cycle $\leq 2\%$.

B. $R_{\theta JA}$ is the sum of the junction-to-lead and lead-to-ambient thermal resistance, where the lead thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JL}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

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■ Typical Performance Characteristics

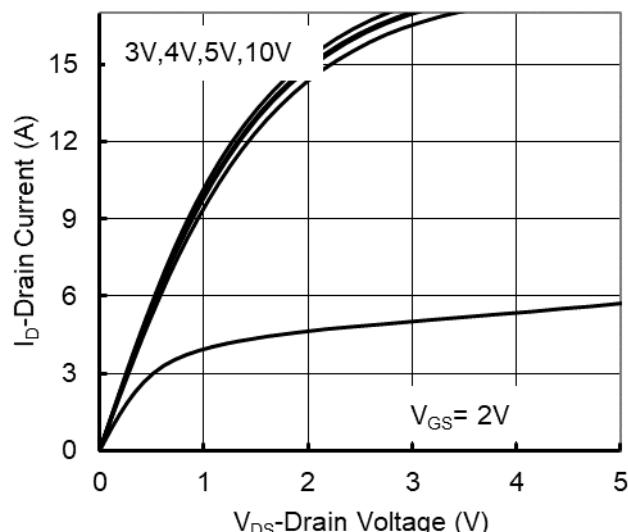


Figure 1. Output Characteristics

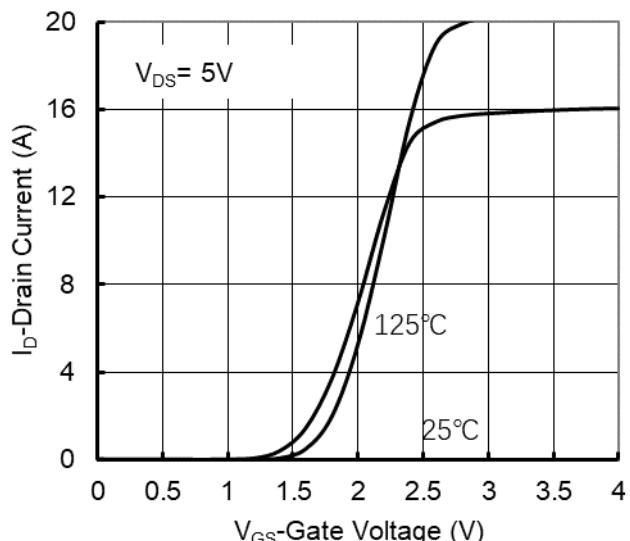


Figure 2. Transfer Characteristics

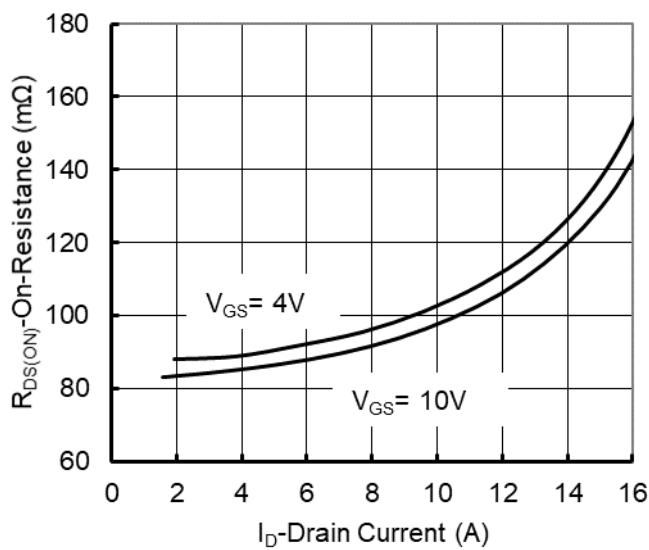


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

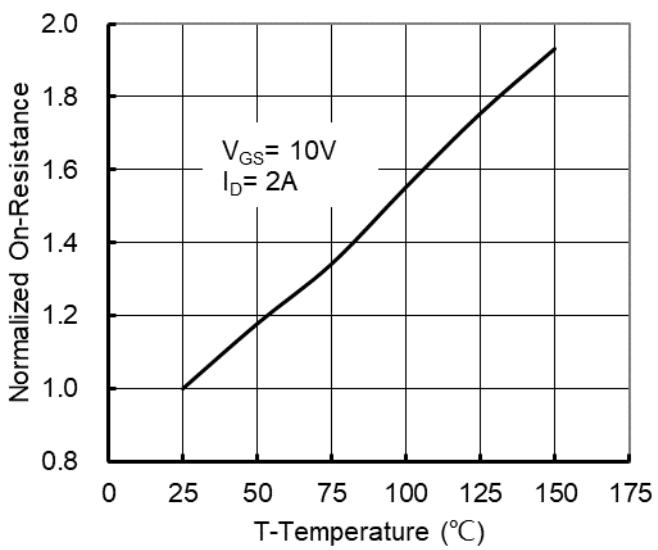


Figure 4: On-Resistance vs. Junction Temperature

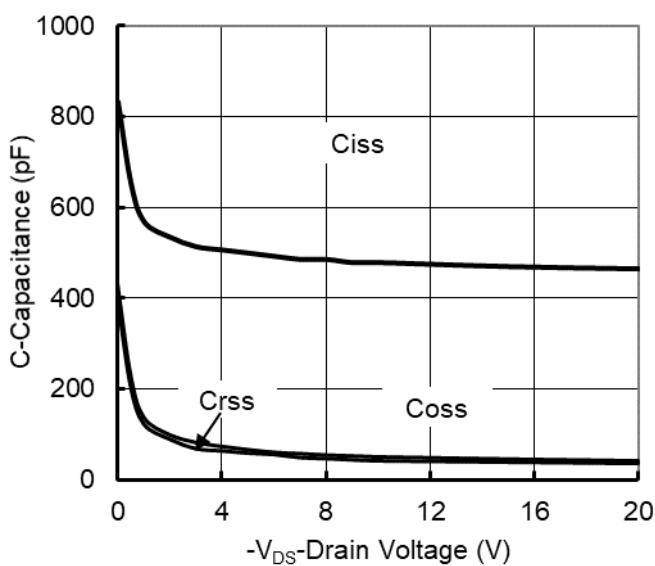


Figure 5. Capacitance Characteristics

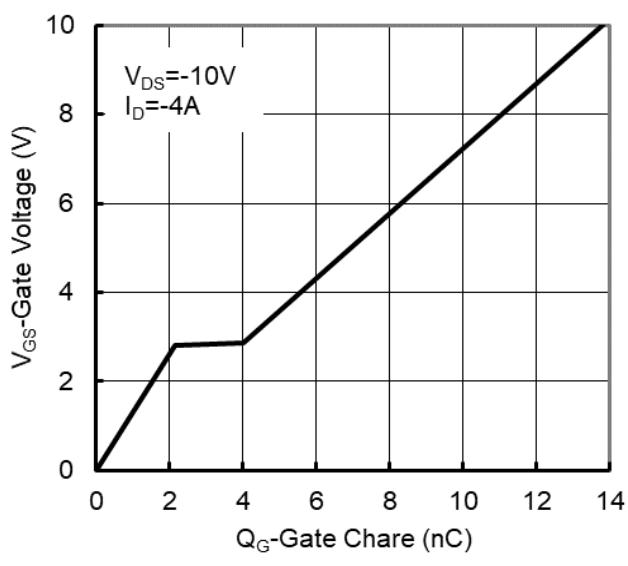
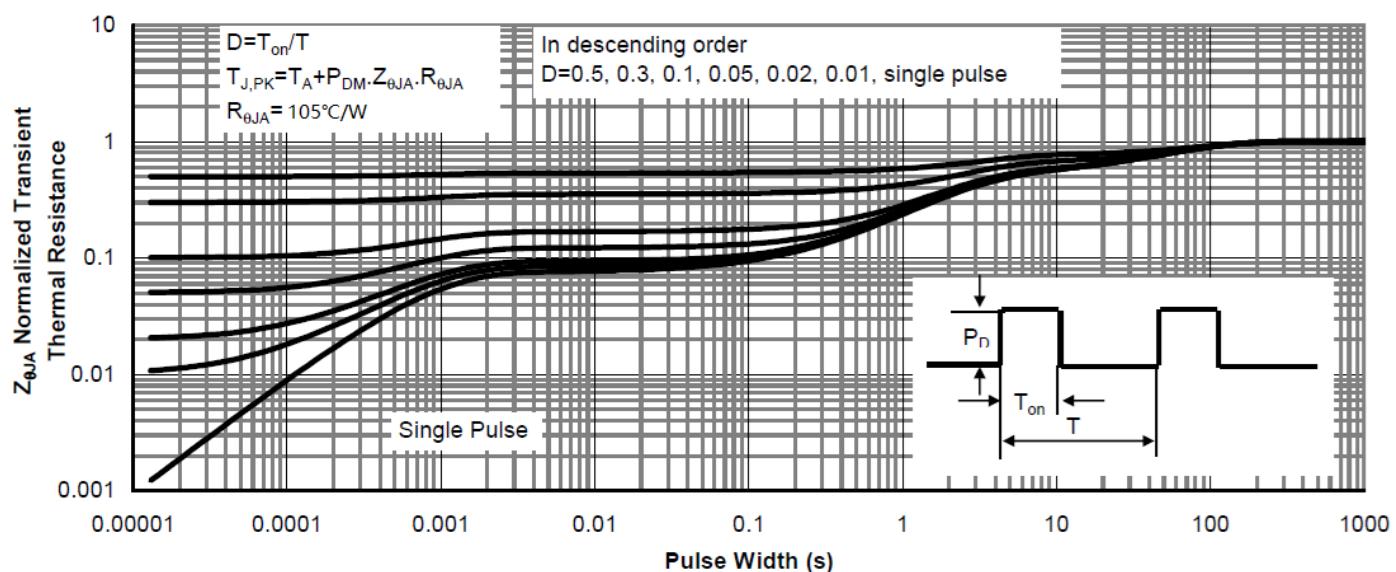
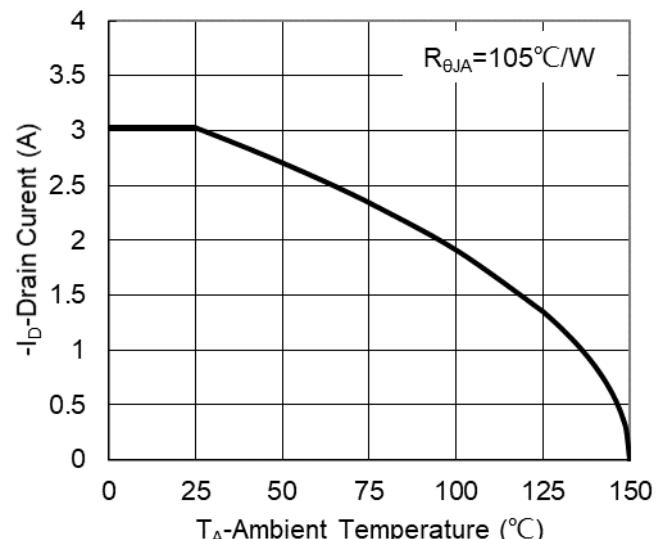
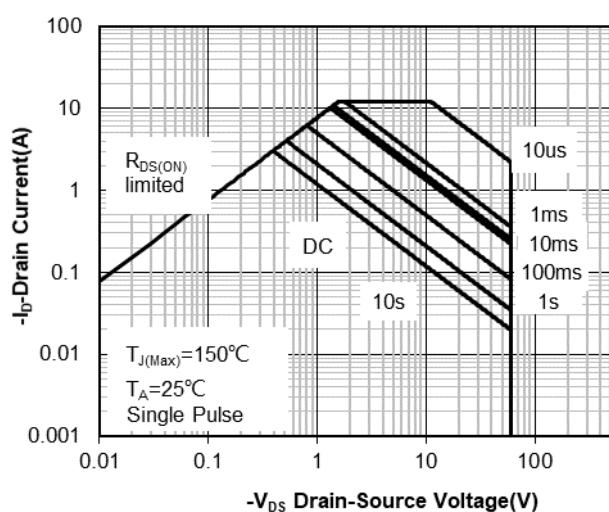


Figure 6. Gate Charge

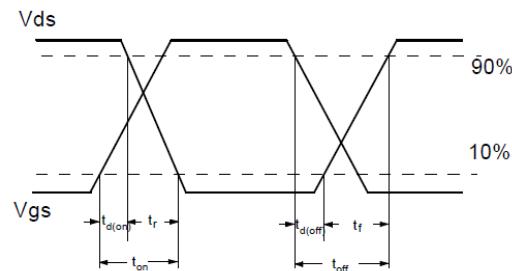
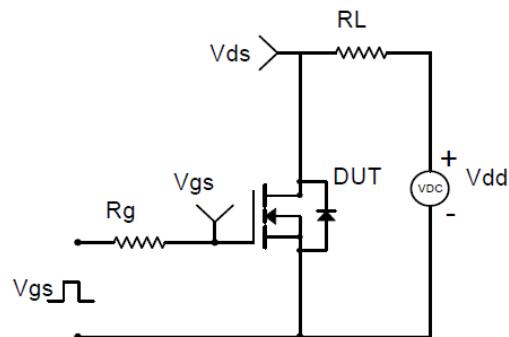
N-Channel Enhancement Mode Field Effect Transistor

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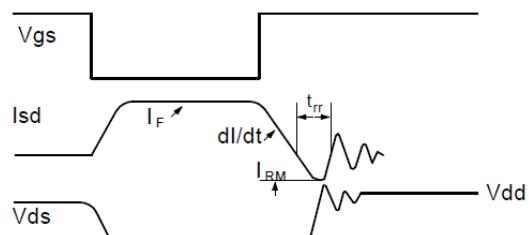
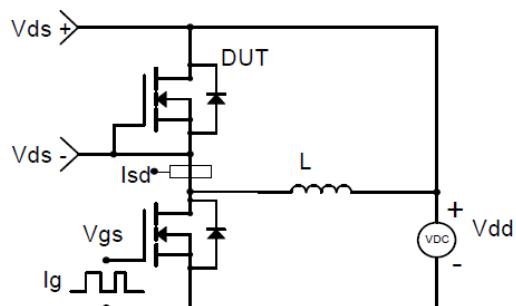


N-Channel Enhancement Mode Field Effect Transistor

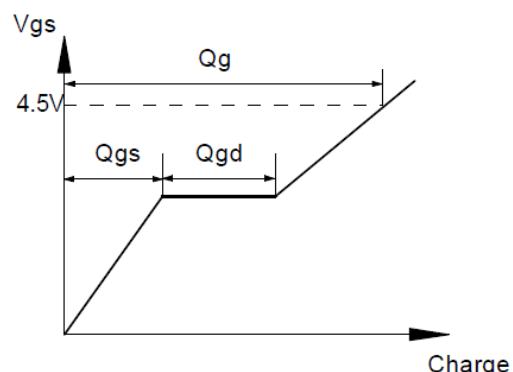
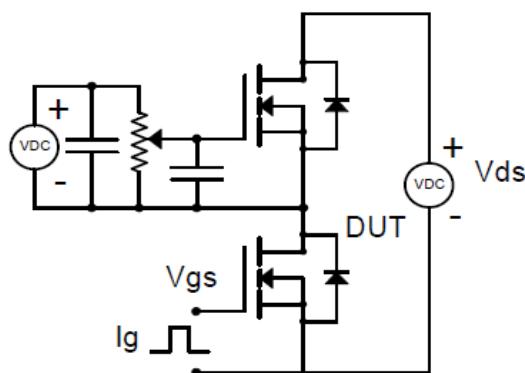
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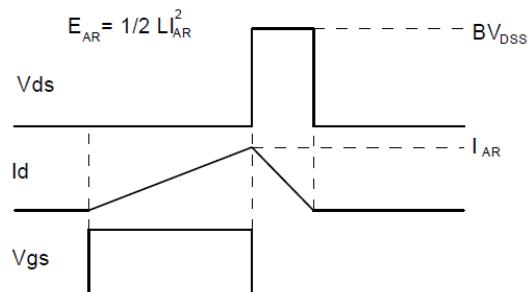
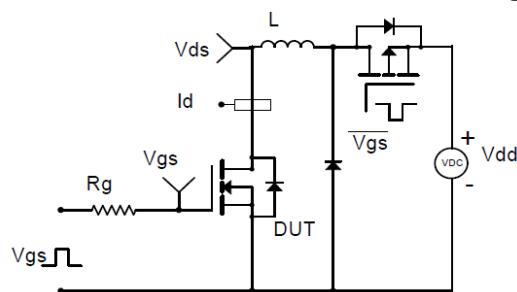
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Gate Charge Test Circuit & Waveform

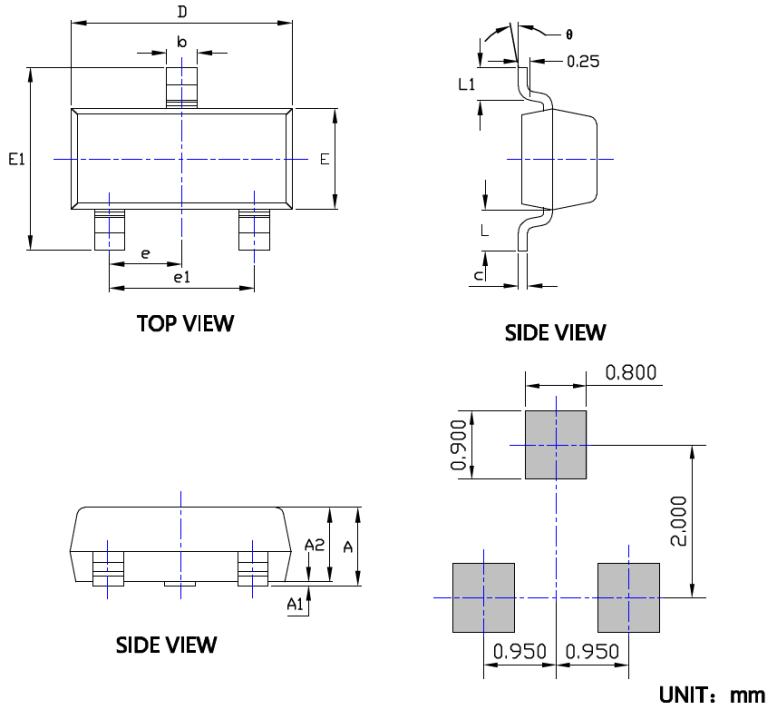


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

N-Channel Enhancement Mode Field Effect Transistor

RC03N06B

■ SOT-23 Package Information



SYMBOL	INCHES		Millimeter	
	MIN.	MAX.	MIN.	MAX.
A	0.035	0.045	0.900	1.150
A1	0.000	0.004	0.000	0.100
A2	0.035	0.041	0.900	1.050
b	0.012	0.020	0.300	0.500
c	0.004	0.008	0.100	0.200
D	0.110	0.118	2.800	3.000
E	0.047	0.055	1.200	1.400
E1	0.089	0.100	2.250	2.550
e	0.037TYP		0.950TYP	
e1	0.071	0.079	1.800	2.000
L	0.022REF		0.550REF	
L1	0.012	0.200	0.300	0.500
θ	0°	8°	0°	8°

NOTE:

- 1.PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
- 2.TOLERANCE 0.1mm UNLESS OTHERWISE SPECIFIED.
- 3.THE PAD LAYOUT IS FOR REFERENCE PURPOSES ONLY.